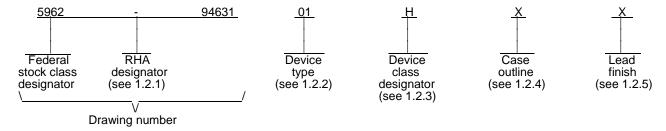
LTR								F	REVISI	ONS										
1	DESCRIPTION						DA	TE (YI	R-MO-	-DA)		APPF	ROVE)						
А	Table I, change Capacitive load maximum limit. 98-11-09							11-09	09 K. A. Cottongim		im									
В		Add device type 02, case outline Y, and vendor CAGE 51651.							04-04-02		Raymond Monnin									
С	Table I, Input ripple current test for device type 02: Add new note 3 and new test limits. Renumber remaining notes to table I in sequence after note 3.						04-04-02		Raymond Monnin											
D		Added footnote 1 to table II, under group C end-point electricals. Updated drawing paragraphssld							12-1	11-01		С	harles	F. Sa	ffle					
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SHEET REV STATU OF SHEETS PMIC N/A STA MICR DR THIS E AV FOR U DEPA AND AGE DEPARTMENT	ANDAR OCIRC AWING DRAWIN AILABL JSE BY ARTMEN NCIES INT OF	IG IS E ALL NTS OF TH		SHE PRE Stev CHE Mic	EFT EPARE CKEE Chael Chael CMAN CMAN CMAN CMAN CMAN CMAN CMAN CMAN	Ouncar O BY Jones ED BY Cotton	gim		3	MIC SIN	5 CRO	CIRCE CH.	DLA IDLUM DE I/WW	8 LAND IBUS w.lan , HYI EL, I	9 ANE, OHIO	D MAFO 432	RITIM 218-3 me.dla	12 E 990 a.mil/		.Т,
SHEET REV STATU OF SHEETS PMIC N/A STA MICR DR THIS E AV FOR U DEPA AND AGE DEPARTMENT	ANDAR OCIRC AWING DRAWIN AILABL JSE BY ARTMEN NCIES	IG IS E ALL NTS OF TH		SHE PRE Stev CHE Mic	EPARE PARE CKEE Chael C	DUNCAR D BY Jones ED BY Cotton	gim	2	3	MIC SIN	5 CRO	CIRCE CH	DLA I	8 LAND IBUS w.lan , HYI EL, I	9 ANE, OHIO	10 MAFO 433 maritim D, LIN	RITIM 218-3 me.dla	12 E 990 a.mil/	ER	

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1. SCOPE

- 1.1 <u>Scope</u>. This drawing documents five product assurance classes as defined in paragraph 1.2.3 and MIL-PRF-38534. A choice of case outlines and lead finishes which are available and are reflected in the Part or Identifying Number (PIN). When available, a choice of radiation hardness assurance levels are reflected in the PIN.
 - 1.2 PIN. The PIN shall be as shown in the following example:



- 1.2.1 <u>Radiation hardness assurance (RHA) designator</u>. RHA marked devices shall meet the MIL-PRF-38534 specified RHA levels and shall be marked with the appropriate RHA designator. A dash (-) indicates a non-RHA device.
 - 1.2.2 <u>Device type(s)</u>. The device type(s) identify the circuit function as follows:

Device type	Generic number	<u>Circuit function</u>
01 02	ASA2812S/CH DAC2812SH	DC/DC converter, 5 W, 12 V output DC/DC converter, 5.4 W, 12 V output

1.2.3 <u>Device class designator</u>. This device class designator shall be a single letter identifying the product assurance level. All levels are defined by the requirements of MIL-PRF-38534 and require QML Certification as well as qualification (Class H, K, and E) or QML Listing (Class G and D). The product assurance levels are as follows:

Device class	Device performance documentation
К	Highest reliability class available. This level is intended for use in space applications.
Н	Standard military quality class level. This level is intended for use in applications where non-space high reliability devices are required.
G	Reduced testing version of the standard military quality class. This level uses the Class H screening and In-Process Inspections with a possible limited temperature range, manufacturer specified incoming flow, and the manufacturer guarantees (but may not test) periodic and conformance inspections (Group A, B, C, and D).
E	Designates devices which are based upon one of the other classes (K, H, or G) with exception(s) taken to the requirements of that class. These exception(s) must be specified in the device acquisition document; therefore the acquisition document should be reviewed to ensure that the exception(s) taken will not adversely affect system performance.
D	Manufacturer specified quality class. Quality level is defined by the manufacturers internal, QML certified flow. This product may have a limited temperature range.

1.2.4 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

Outline letter	Descriptive designator	<u>Terminals</u>	Package style
Χ	See figure 1	8	Dual-in-line
Υ	See figure 1	8	Dual-in-line

1.2.5 Lead finish. The lead finish shall be as specified in MIL-PRF-38534.

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1.3 Absolute maximum ratings. 1/	
Input voltage range	-0.5 V dc to +50 V dc (continuous) 80 V (100 ms) 4 W +300°C -65°C to +150°C
1.4 Recommended operating conditions.	
Input voltage range: Device type 01 Device type 02 Output power: 2/	+16 V dc to +40 V dc +11 V dc to +50 V dc
Device type 01 Device type 02 Case operating temperature range (T _C)	≤ 5 W ≤ 5.4 W -55°C to +125°C

2. APPLICABLE DOCUMENTS

2.1 <u>Government specification, standards, and handbooks</u>. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38534 - Hybrid Microcircuits, General Specification for.

DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.

MIL-STD-1835 - Interface Standard for Electronic Component Case Outlines.

DEPARTMENT OF DEFENSE HANDBOOKS

MIL-HDBK-103 - List of Standard Microcircuit Drawings.

MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at https://assist.dla.mil/quicksearch/ or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 <u>Order of precedence</u>. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 <u>Item requirements</u>. The individual item performance requirements for device classes D, E, G, H, and K shall be in accordance with MIL-PRF-38534. Compliance with MIL-PRF-38534 shall include the performance of all tests herein or as designated in the device manufacturer's Quality Management (QM) plan or as designated for the applicable device class. The manufacturer may eliminate, modify, or optimize the tests and inspections herein, however, the performance requirements as defined in MIL-PRF-38534 shall be met for the applicable device class. In addition, the modification in the QM plan shall not affect the form, fit, or function of the device for the applicable device class.

^{2/} Derate output power linearly above case temperature +125°C to 0 at +135°C.

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^{1/} Stresses above the absolute maximum ratings may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.

- 3.2 <u>Design, construction, and physical dimensions</u>. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38534 and herein.
 - 3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.4 herein and figure 1.
 - 3.2.2 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 2.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.
- 3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are defined in table I.
- 3.5 <u>Marking of device(s)</u>. Marking of device(s) shall be in accordance with MIL-PRF-38534. The device shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's vendor similar PIN may also be marked.
- 3.6 <u>Data</u>. In addition to the general performance requirements of MIL-PRF-38534, the manufacturer of the device described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, for each device type listed herein. Also, the data should include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DLA Land and Maritime -VA) upon request.
- 3.7 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to supply to this drawing. The certificate of compliance (original copy) submitted to DLA Land and Maritime -VA shall affirm that the manufacturer's product meets the performance requirements of MIL-PRF-38534 and herein.
- 3.8 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-PRF-38534 shall be provided with each lot of microcircuits delivered to this drawing.

4. VERIFICATION

- 4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with MIL-PRF-38534 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.
 - 4.2 <u>Screening</u>. Screening shall be in accordance with MIL-PRF-38534. The following additional criteria shall apply:
 - a. Pre-seal burn-in test, method 1030 of MIL-STD-883. (optional for class H)
 - (1) Test condition C or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DLA Land and Maritime -VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1030 of MIL-STD-883.
 - (2) T_A as specified in accordance with table I of method 1015 of MIL-STD-883.
 - b. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DLA Land and Maritime -VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
 - (2) T_A as specified in accordance with table I of method 1015 of MIL-STD-883.
 - c. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

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Output voltage		$-55^{\circ}\text{C} \le T_{\text{C}} \le +125^{\circ}\text{C}$ $V_{\text{IN}} = 28 \text{ V dc } \pm 5\%, \text{ C}_{\text{L}} = 0$	subgroups	typoo			Unit
Output voltage		unless otherwise specified	3	types	Min	Max	
	V _{OUT}	I _{OUT} = 0	1	01,02	11.88	12.12	V
			2,3		11.76	12.24	
Output current 1/	l _{OUT}	V _{IN} = 16, 28, and 40 V dc	1,2,3	01		417	mA
				02		450	
Output ripple voltage 2/	V_{RIP}	V _{IN} = 16, 28, and 40 V dc,	1	01,02		200	mVp-p
		B.W. = 20 Hz to 2 MHz,	2,3			290	290
ine regulation	VR _{LINE}	V _{IN} = 16, 28, and 40 V dc,	1	01,02		±25	mV
		$I_{OUT} = 0$, 208, and 417 mA	2,3			±50	
oad regulation	VR_{LOAD}	V _{IN} = 16, 28, and 40 V dc,	1	01,02		±25	mV
		$I_{OUT} = 0$, 208, and 417 mA	2,3			±50	
nput current	I _{IN}	I _{OUT} = 0 , Inhibit (pin 5) tied	1,2,3	01		18	mA
		to input return (pin 7)		02		2.5	
		I _{OUT} = 0 , Inhibit (pin 5) = open		01,02		50	
nput ripple current 2/ 3/	I _{RIP}	I _{OUT} = 417 mA,	1,2,3	01		100	mAp-p
		B.W. = 20 Hz to 2 MHz	1	02		125	
			2,3			200	
Efficiency	Eff	I _{OUT} = 417 mA	1	01	71		%
				02	62		
			2,3	01	68		
				02	60		
solation	ISO	Input to output or any pin to case (except pin 8) at 500V dc, T _C = +25°C	1	01,02	100		ΜΩ
Capacitive load 4/5/ See footnotes at end of table.	CL	No effect on dc performance, T _C = +25°C	4	01,02		100	μF

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MICROCIRCUIT DRAWING

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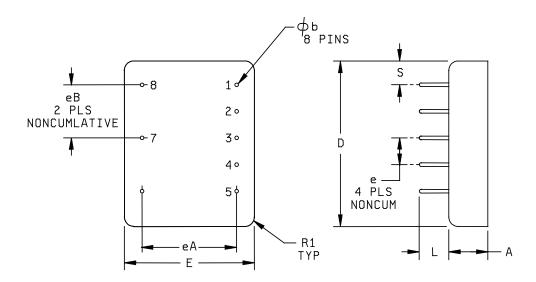
	TABL	E I. Electrical performance	e characteristics	- Continued.			
Test	Symbol	Conditions $-55^{\circ}C \le T_C \le +125^{\circ}C$	Group A subgroup			mits	Unit
		V_{IN} = 28 V dc ±5%, C_L = unless otherwise specific			Min	Max	
Power dissipation load	P _D	Overload 6/	1,2,3	01,02		4.0	W
fault <u>7</u> /		Short circuit				2.0	
Switching frequency	Fs	I _{OUT} = 417 mA	4,5,6	01	500	600	kHz
			4	02	370	430	
Output response to step	VO _{TLOAD}	208 mA to/from 417 mA	4,5,6	01	-450	+450	mV pk
transient load changes <u>8</u> /				02	-700	+700	
		0 mA to/from 208 mA		01	-750	+750	
				02	-1100	+1100	
Recovery time, step transient load changes	TT _{LOAD}	208 mA to/from 417 mA	4,5,6	01		100	μS
8/ 9/				02		200	
		0 mA to/from 208 mA	4,5,6	01		1	ms
				02		1.25	
		208 mA to/from 0 mA	4,5,6	01		1	_
				02		1.25	
Output response transient step line changes	VO _{TLINE}	Input step 16 to 40 V dc, I _{OUT} = 417 mA <u>5</u> / <u>10</u> /	4,5,6	01		1000	mV pk
step line changes		1001 – 417 IIIA <u>3</u> 7 <u>10</u> 7		02		500	
		Input step 40 to 16 V dc, $I_{OUT} = 417 \text{ mA } \frac{5}{10}$	4,5,6	01		-1000	
		1001 – 417 111A <u>3</u> 7 <u>10</u> 7		02		-500	
Recovery time transient step line changes	TT _{LINE}	Input step 16 to 40 V dc, I _{OUT} = 417 mA <u>5</u> / <u>9</u> / <u>10</u> /	4,5,6	01		800	μs
step line changes		1001 – 417 IIIA <u>3</u> 1 <u>9</u> 1 <u>10</u> 1		02		200	
Turn on overshoot	Vtonos	I _{OUT} = 0 mA	4,5,6	01		600	mV pk
				02		200	_ [
		I _{OUT} = 417 mA		01		600	
				02		200	
See footnotes at end of tab	e.						
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	TABL	E I. Electrical performance ch	aracteristics - (Continued.			
Test	Symbol	Conditions	Group A	Device	Limits		Unit
		-55° C \leq T _C \leq +125 $^{\circ}$ C V _{IN} = 28 V dc \pm 5%, C _L = 0 unless otherwise specified	subgroups	types	Min	Max	
Turn on delay 11/	Ton _D	I _{OUT} = 0 and 417 mA	4,5,6	01		25	ms
				02		60	
Load fault recovery <u>5</u> / <u>7</u> /	Tr _{LF}		4,5,6	01		25	ms
				02		60	

- 1/ Parameter guaranteed by line and load regulation tests.
- 2/ Bandwidth guaranteed by design. Tested for 20 kHz to 2 MHz.
- 3/ Device type 02 measurement is taken with an input series inductance of 2 μH.
- 4/ Capacitive load may be any value from 0 to the maximum limit without compromising dc performance. A capacitive load in excess of the maximum limit will not disturb loop stability but may interfere with the operation of the load fault detection circuitry, appearing as a short circuit during turn-on.
- 5/ Parameter shall be tested as part of design characterization and after design or process changes. Thereafter, parameters shall be guaranteed to the limits specified in table 1.
- 6/ An overload is that condition with a load in excess of the rated load but less than that necessary to trigger the short circuit protection and is the condition of maximum power dissipation.
- 7/ Device type 02 has an internal shutdown feature that turns off the device for 200 milliseconds with continuous restart attempts of 10 milliseconds.
- 8/ Load step transition time between 2 and 10 microseconds. Device type 02 tested at 30 microseconds transition time.
- $\underline{9}/$ Recovery time is measured from the initiation of the transient to where V_{OUT} has returned to within \pm 1 percent of V_{OUT} at 50 percent load.
- 10/ Input step transition time between 2 and 10 microseconds. Device type 02 tested at 30 microseconds transition time.
- 11/ Turn-on delay time measurement is for either a step application of power at the input or the removal of a ground signal from the inhibit pin (pin 5) while power is applied to the input.

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Case outline X.



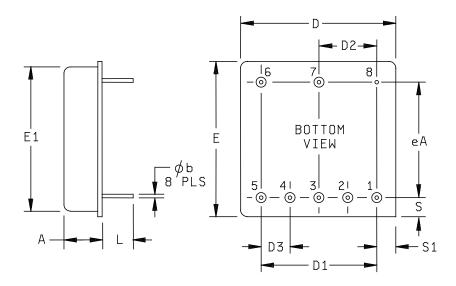
	Millin	neters	Inc	hes
Symbol	Min	Max	Min	Max
Α		6.86		.270
Øb	0.56	0.71	.022	.028
D		27.31		1.075
eA	20.19	20.45	.795	.805
е	4.95	5.21	.195	.205
eB	10.03	10.29	.395	.405
Е		27.31		1.075
L		5.59		.220
R1	2.03	2.54	.080	.100
S	3.23	3.48	.127	.137

NOTES:

- 1. The U.S. government preferred system of measurement is the metric SI. This item was designed using inch-pound units of measurement. In case of problems involving conflicts between the metric and inch-pound units, the inch-pound units shall rule.
- 2. Lead identification for reference only.
- 3. Case outline X weight: 20 grams maximum.

FIGURE 1. Case outline(s).

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Symbol	Millimeters		Inc	hes
_	Min	Max	Min	Max
Α		9.27		.365
∅b	0.38	0.89	.015	.035
D/E	25.15	25.65	0.990	1.010
D1	20.19	20.45	.795	.805
D2			.390	.410
D3			.190	.210
E	25.15	25.65	0.990	1.010
E1	23.50	0 REF	.925	REF
eA	20.19	20.45	.795	.805
S/S1	2.29	2.79	.090	.110
L	4.95	5.46	.195	.215

NOTES:

- 1. ESD triangle indicates pin 1.
- 2. The U. S. Government preferred system of measurement is the metric SI. This item was designed using inch-pound units of measurement. In case of problems involving conflicts between the metric and inch-pound units, the inch-pound units shall take precedence.
- 3. Pin numbers are for reference only.
- 4. Case outline Y weight: 15 grams maximum.

FIGURE 1. Case outline(s) - Continued.

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Device types	01	02
Case outlines	х	Y
Terminal number	Terminal symbol	Terminal symbol
1	Output	Output
2	Output return	Output return
3	No connection	No connection
4 <u>1</u> /	No connection	Adjust/Comp
5	Inhibit	Inhibit
6	Input	Input
7	Input return	Input return
8	Case ground	Case ground

NOTE:

FIGURE 2. Terminal connections.

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^{1/} Device type 02 has an optional output adjust pin. Connection to this pin is not required.

TABLE II. Electrical test requirements.

MIL-PRF-38534 test requirements	Subgroups (in accordance with MIL-PRF-38534, group A test table)
Interim electrical parameters	
Final electrical parameters	1*,2,3,4,5,6
Group A test requirements	1,2,3,4,5,6
Group C end-point electrical 1/ parameters	1,2,3,4
End-point electrical parameters for radiation hardness assurance (RHA) devices	Not applicable

- 1/ As a minimum, for all Group C testing performed after (12-11-01) manufacturers shall perform subgroups 1, 2, and 3 from the Group A electrical test table (Table C-Xa of MIL-PRF-38534).
- * PDA applies to subgroup 1.
- 4.3 <u>Conformance and periodic inspections</u>. Conformance inspection (CI) and periodic inspection (PI) shall be in accordance with MIL-PRF-38534 and as specified herein.
 - 4.3.1 Group A inspection (CI). Group A inspection shall be in accordance with MIL-PRF-38534 and as follows:
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 7, 8, 9, 10, and 11 shall be omitted.
 - 4.3.2 Group B inspection (PI). Group B inspection shall be in accordance with MIL-PRF-38534.
 - 4.3.3 Group C inspection (PI). Group C inspection shall be in accordance with MIL-PRF-38534 and as follows:
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DLA Land and Maritime -VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
 - (2) T_A as specified in accordance with table I of method 1005 of MIL-STD-883.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.
 - 4.3.4 Group D inspection (PI). Group D inspection shall be in accordance with MIL-PRF-38534.
 - 4.3.5 Radiation Hardness Assurance (RHA) inspection. RHA inspection is not currently applicable to this drawing.

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- 5. PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38534.
- 6. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated as specified in MIL-PRF-38534.
- 6.4 <u>Record of users</u>. Military and industrial users shall inform DLA Land and Maritime when a system application requires configuration control and the applicable SMD to that system. DLA Land and Maritime will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DLA Land and Maritime-VA, telephone (614) 692-0547.
- 6.5 <u>Comments</u>. Comments on this drawing should be directed to DLA Land and Maritime-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-1081.
- 6.6 <u>Sources of supply</u>. Sources of supply are listed in MIL-HDBK-103 and QML-38534. The vendors, listed in MIL-HDBK-103 and QML-38534, have submitted a certificate of compliance (see 3.7 herein) to DLA Land and Maritime-VA and have agreed to this drawing.

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 12-11-01

Approved sources of supply for SMD 5962-94631 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38534 during the next revisions. MIL-HDBK-103 and QML-38534 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DLA Land and Maritime -VA. This information bulletin is superseded by the next dated revisions of MIL-HDBK-103 and QML-38534. DLA Land and Maritime maintains an online database of all current sources of supply at http://www.landandmaritime.dla.mil/Programs/Smcr/.

Standard	Vendor	Vendor
microcircuit drawing	CAGE	similar
PIN <u>1</u> /	number	PIN <u>2</u> /
5962-9463101HXA	52467	ASA2812S/CH
5962-9463102HYA	51651	DAC2812SH
5962-9463102HYC	51651	DAC2812SH

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the Vendor to determine its availability.
- 2/ <u>Caution</u>. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number_	Vendor name <u>and address</u>
51651	M. S. Kennedy Corporation 4707 Dey Road Liverpool, NY 13088
52467	International Rectifier Corporation 2520 Junction Avenue San Jose, CA 95134

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FS600R07A2E3_B31 FZ1600R17HP4_B2 FZ1800R17KF4 FZ2400R17HE4_B9 FZ600R65KE3 DD261N22K DF1000R17IE4 BAT 165

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